

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/786,100	<b>Applicant(s)/Patent under Reexamination</b> YOSHIKAWA ET AL.
	<b>Examiner</b> A. J. HEINZ	<b>Art Unit</b> 2627

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See			
Search			
History	12/24/06		JH